



40V COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	BV _{DSS}	R _{DS(ON)} Max	I _D Max T _A = +25°C		
			(Notes 7 & 9)		
Q1	40V	45mΩ @ V _{GS} = 10V	5.8A		
	40 V	60mΩ @ V _{GS} = 4.5V 4.2A			
Q2	40\/	45mΩ @ V _{GS} = -10V	-5.8A		
	-40V	60mΩ @ V _{GS} = -4.5V	-4.2A		

Description and Applications

This MOSFET is designed to meet the stringent requirements of Automotive applications. It is qualified to AEC-Q101, supported by a PPAP and is ideal for use in:

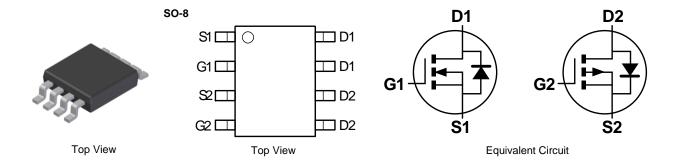
- 3-Phase BLDC Motor
- CCFL Backlighting

Features and Benefits

- Matched N & P R_{DS(ON)} Minimizes Power Losses
- Fast Switching Minimizes Switching Losses
- Dual Device Reduces PCB Area
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability
- PPAP Capable (Note 4)

Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
 UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish Matte Tin Annealed over Copper Leadframe.
 Solderable per MIL-STD-202, Method 208 (§3)
- Weight: 0.074 grams (Approximate)



Ordering Information (Note 5)

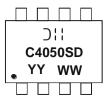
- 1			
	Part Number	Case	Packaging
	DMC4050SSDQ-13	SO-8	2,500/Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. Automotive products are AEC-Q101 qualified and are PPAP capable. Refer to http://www.diodes.com/quality/product_compliance_definitions/.
- $5. \ For packaging \ details, go \ to \ our \ website \ at \ http://www.diodes.com/products/packages.html.$



Marking Information



OH = Manufacturer's Marking
C4050SD = Product Type Marking Code
YYWW = Date Code Marking
YY or YY= Year (ex: 16 = 2016)
WW = Week (01 - 53)

Maximum Ratings (@ $T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic			Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage			V _{DSS}	40	-40	V
Gate-Source Voltage			V _{GSS}	±20	±20	V
Continuous Drain Current	V _{GS} = 10V	(Notes 7 & 9)	I _D	5.8	-5.8	A
		T _A = +70°C (Notes 7 & 9)		4.38	-4.52	
		(Notes 6 & 9)		4.2	-4.2	
		(Notes 6 & 10)		5.3	-5.3	
Pulsed Drain Current	$V_{GS} = 10V$	(Notes 8 & 9)	I_{DM}	24.1	-24.9	
Continuous Source Current (Body Diode) (Notes 7 & 9)		(Notes 7 & 9)	Is	2.5	-2.5	
Pulsed Source Current (Body Diode) (Notes 8 & 9)		(Notes 8 & 9)	I _{SM}	24.1	-24.9	

Thermal Characteristics

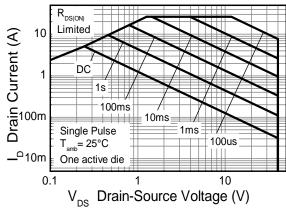
Characteristic	Symbol	N-Channel - Q1	P-Channel - Q2	Unit		
Device Discinction	(Notes 6 & 9)		1.25	10		
Power Dissipation Linear Derating Factor	(Notes 6 & 10)	P_{D}	1.8	14.3	W	
Linear Derailing Factor	(Notes 7 & 9)		2.14	17.2		
	(Notes 6 & 9)		10	°C/W		
Thermal Resistance, Junction to Ambient	(Notes 6 & 10)	$R_{\theta JA}$	7			
	(Notes 7 & 9)		5			
Thermal Resistance, Junction to Lead (Notes 6 & 11)		$R_{\theta JL}$	51			
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to	+150	°C		

Notes:

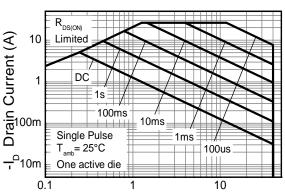
- 6. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 7. Same as Note (6), except the device is measured at $t \leq 10 \mbox{ sec.}$
- 8. Same as Note (6), except the device is pulsed with D = 0.02 and pulse width $300\mu s$.
- 9. For a dual device with one active die.
- 10. For a device with two active die running at equal power.
- 11. Thermal resistance from junction to solder-point (at the end of the drain lead).



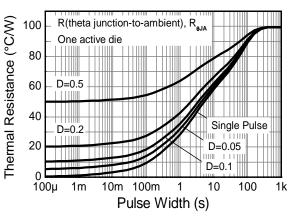
Thermal Characteristics (Continued)



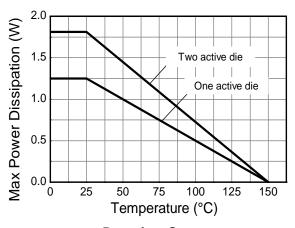
N-channel Safe Operating Area



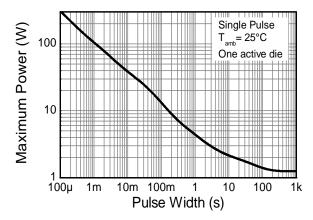
-V_{DS} Drain-Source Voltage (V) **P-channel Safe Operating Area**



Transient Thermal Impedance



Derating Curve



Pulse Power Dissipation



Electrical Characteristics (Q1 N-Channel) (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 12)							
Drain-Source Breakdown Voltage	BV _{DSS}	40	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	_	_	1.0	μA	$V_{DS} = 40V$, $V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 12)							
Gate Threshold Voltage	$V_{GS(TH)}$	8.0	1.3	1.8	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$	
Static Drain-Source On-Resistance			20	45	mΩ	$V_{GS} = 10V$, $I_D = 3A$	
Static Brain-Source On-Nesistance	R _{DS(ON)}		33	60	11122	$V_{GS} = 4.5V, I_D = 3A$	
Forward Transfer Admittance	Y _{FS}	_	12.6	_	S	$V_{DS} = 5V, I_{D} = 3A$	
Diode Forward Voltage (Note 12)	V _{SD}	_	0.7	1.0	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 13)							
Input Capacitance	C _{ISS}	_	1,790.8	_	pF), 20),), 0),	
Output Capacitance	Coss	_	160.6	_	pF	$V_{DS} = 20V, V_{GS} = 0V,$ f = 1.0MHz	
Reverse Transfer Capacitance	C _{RSS}	_	120.5	_	pF	1 = 1.000112	
Gate Resistance	R _G	_	1.03	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge	Q_{G}	_	37.56	_	nC	V 40V V 20V	
Gate-Source Charge	Q_GS	_	7.8	_	nC	$V_{GS} = 10V, V_{DS} = 20V,$	
Gate-Drain Charge	Q_{GD}	_	6.6	_	nC	$I_D = 3A$	
Turn-On Delay Time	t _{D(ON)}	_	8.08	_	ns	$V_{GS} = 10V, V_{DS} = 20V,$ $I_{D} = 3A$	
Turn-On Rise Time	t _R	_	15.14	_	ns		
Turn-Off Delay Time	t _{D(OFF)}	_	24.29	_	ns		
Turn-Off Fall Time	t _F	_	5.27	_	ns		

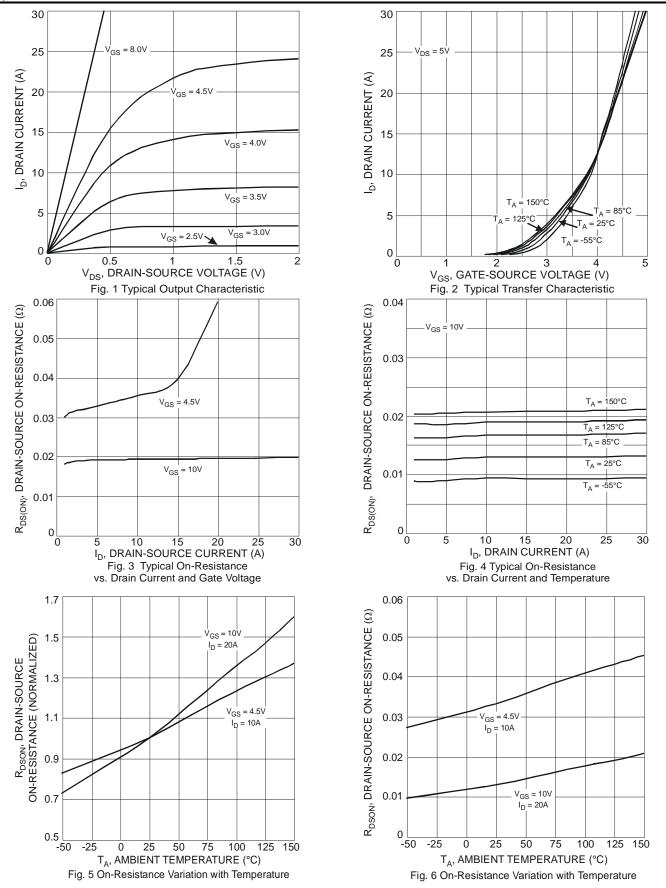
Electrical Characteristics (Q2 P-Channel) (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 12)							
Drain-Source Breakdown Voltage	BV _{DSS}	-40		l	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	_		-1.0	μΑ	$V_{DS} = -40V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_		±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 12)							
Gate Threshold Voltage	$V_{GS(TH)}$	-0.8	-1.3	-1.8	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
Static Drain-Source On-Resistance	D- even		28	45	mΩ	$V_{GS} = -10V, I_D = -3A$	
Static Dialii-Source Off-Resistance	R _{DS(ON)}	_	30	60	11122	$V_{GS} = -4.5V$, $I_{D} = -3A$	
Forward Transfer Admittance	Y _{FS}	_	16.6		S	$V_{DS} = -5V, I_{D} = -3A$	
Diode Forward Voltage (Note 12)	V_{SD}	_	-0.7	-1.0	٧	$V_{GS} = 0V, I_{S} = -1A$	
DYNAMIC CHARACTERISTICS (Note 13)							
Input Capacitance	C _{ISS}	_	1,643.17	_	pF), 20V, V, 0V,	
Output Capacitance	Coss	_	179.13		pF	$V_{DS} = -20V, V_{GS} = 0V,$ -f = 1.0MHz	
Reverse Transfer Capacitance	C _{RSS}	_	127.82	l	pF	1 – 1.000112	
Gate Resistance	R _G	_	6.43	l	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge	Q_{G}	_	33.66		nC	10)/)/ 20)/	
Gate-Source Charge	Q _{GS}	_	5.54	_	nC	$V_{GS} = -10V, V_{DS} = -20V,$	
Gate-Drain Charge	Q_{GD}	_	7.30	_	nC	$I_D = -3A$	
Turn-On Delay Time	t _{D(ON)}	_	6.85		ns		
Turn-On Rise Time	t _R	_	14.72	_	ns	$V_{GS} = -10V, V_{DS} = -20V,$	
Turn-Off Delay Time	t _{D(OFF)}	_	53.65	_	ns	$I_D = -3A$	
Turn-Off Fall Time	t _F	_	30.86	_	ns		

12. Short duration pulse test used to minimize self-heating effect. 13. Guaranteed by design. Not subject to production testing. Notes:



Typical Characteristics (Q1 N-Channel)





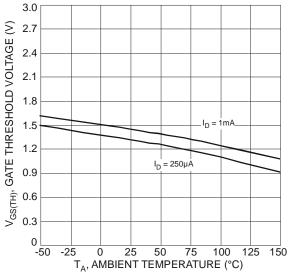
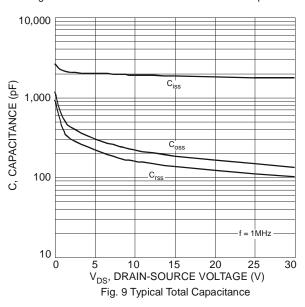
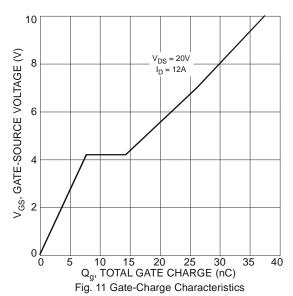
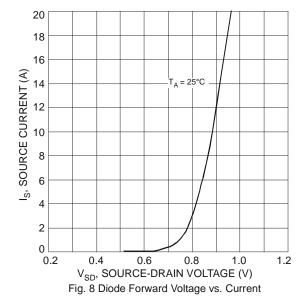
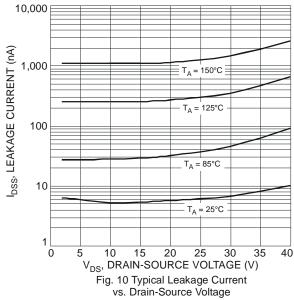


Fig. 7 Gate Threshold Variation vs. Ambient Temperature











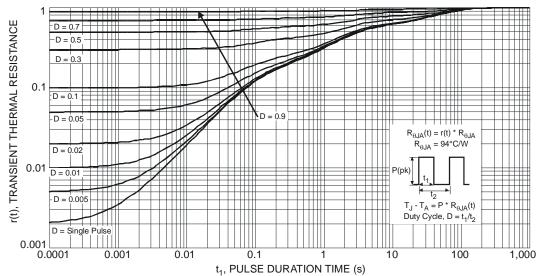
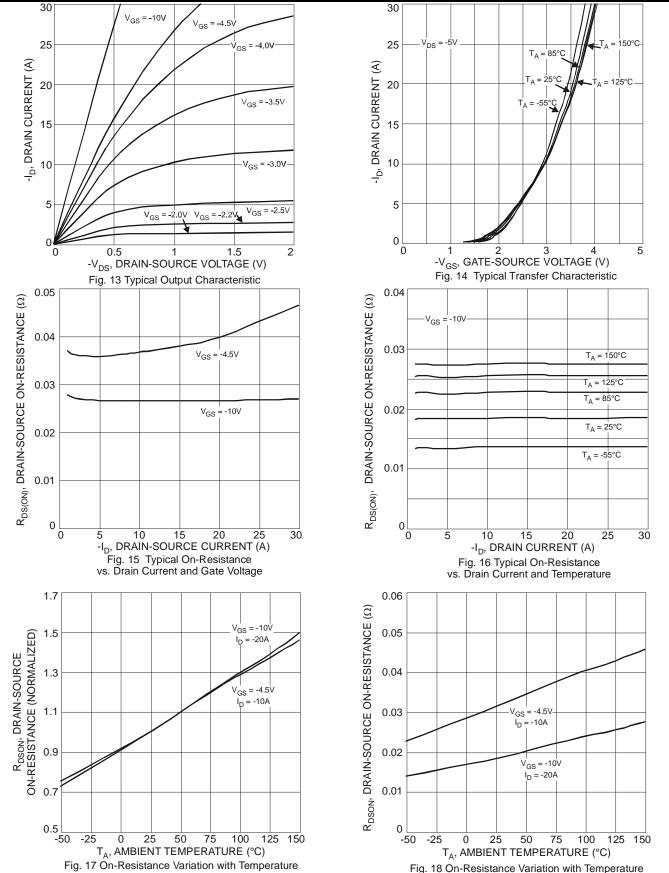


Fig. 12 Transient Thermal Response



Typical Characteristics (Q2 P-Channel)





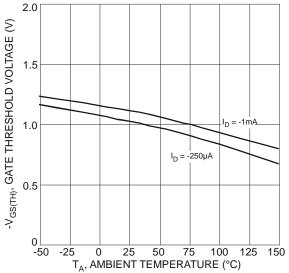
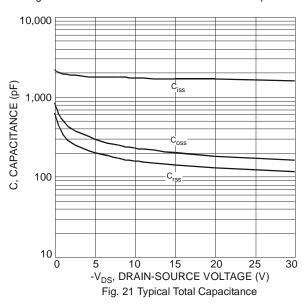
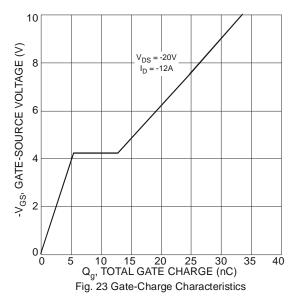
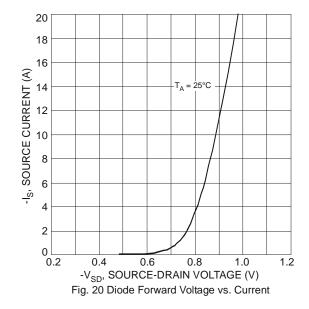
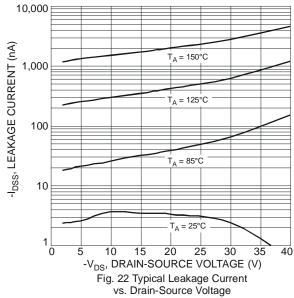


Fig. 19 Gate Threshold Variation vs. Ambient Temperature

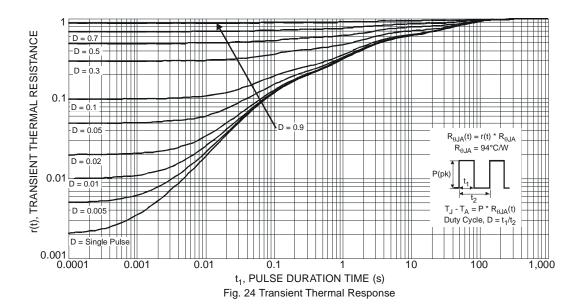










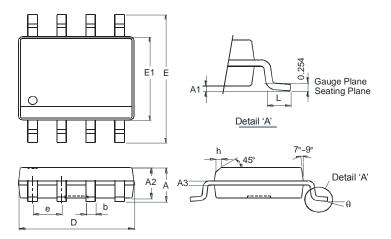




Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8

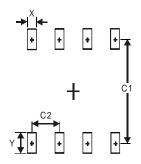


SO-8					
Dim	Min	Max			
Α	_	1.75			
A1	0.10	0.20			
A2	1.30	1.50			
A3	0.15	0.25			
b	0.3 0.5				
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85 3.95				
е	1.27 Typ				
h	- 0.35				
L	0.62 0.82				
θ	0° 8°				
All Dimensions in mm					

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8



Dimensions	Value (in mm)			
Х	0.60			
Y	1.55			
C1	5.4			
C2	1.27			



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